

INFORMATION
DISCLOSURE
CITATION

Applicant: Simon FENNEY, et al

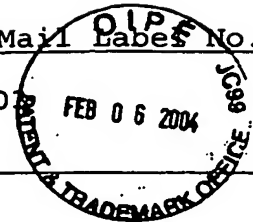
Ser.No. : 10/621 111

Filed : July 16, 2004

Conf. No.: 8439

Atty.Ref.: R&G 361

Group : 2124



U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Date	Name	Class	Sub Class	Filing Date
<i>kw</i>	AA 4 949 424	Sep 1999	Cabral, et al			
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Sub Class	Translation Yes No
<i>kw</i>	AL WO 95/27268	Oct 1995	WIPO			
<i>kw</i>	AM EP 1 004 094 B1	Oct 2002	EPO			
	AN					
	AO					
	AP					

OTHER DOCUMENTS (Including Author, Title, Date, Pages, Etc.)

<i>kw</i>	AR	BLINN, James F.; "Simulation of Wrinkled Surfaces", SIGGRAPH 1978, pp. 286-292
<i>kw</i>	AS	PEERCY, Mark, et al; "Efficient Bump Mapping Hardware", SIGGRAPH 1997, pp. 303-306

EXAMINER

Kimboon Nguyen

DATE CONSIDERED

11-8-05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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U.S. PATENT DOCUMENTS

Examiner Initials	Document Number	Date	Name	Class	Sub Class	Filing Date
<i>kw</i>	AA 6 337 684	01/2002	Dyer et al.			
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Sub Class	Translation Yes No
<i>kw</i>	AL WO 99/09523	02/1999	WIPO			
	AM					
	AN					
	AO					
	AP					

OTHER DOCUMENTS (Including Author, Title, Date, Pages, Etc.)

<i>kw</i>	AR	United Kingdom Patent Office Examination Report dated March 16, 2005 (1 page)
<i>kw</i>	AS	International Preliminary Examining Authority Written Opinion (7 pages)

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Krombh Nguyen

DATE CONSIDERED

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INFORMATION DISCLOSURE CITATION	Applicant: Simon FENNEY et al.
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	Group: 2124

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
<i>16w</i>	AA	6 204 854 B1	03-20-2001	Signes et al.
	AB			
	AC			
	AD			
	AE			
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	AH			
	AI			
	AJ			
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
	AL				
	AM				
	AN				
	AO				

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
<i>16w</i>	AP	International Search Report dated November 6, 2003 (4 pages)
<i>16w</i>	AQ	JEONG-HWAN AHN ET AL: "An efficient geometry compression method for 3D objects in the spherical coordinate system", IMAGE PROCESSING, 10/24/1999 (Abstract 1 page)
EXAMINER SIGNATURE <i>Komondor Agreuer</i>		DATE CONSIDERED 11-8-05

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